| | Application No. | Applicant(s) | |
|--|---|---|--------------------------|
| Notice of Allowability . | 10/768,166 | WU ET AL. | |
| | Examiner | Art Unit | |
| | Kin Chan Chan | 4765 | |
| | Kin-Chan Chen | 1765 | |
| The MAILING DATE of this communication appear All claims being allowable, PROSECUTION ON THE MERITS IS (herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGOT OF THE OFFICE OFFICE OF THE OFFICE OF THE OFFICE OF THE OFFICE | OR REMAINS) CLOSED in or other appropriate comminion is second to the comminion in the comminion is second to the comminion is second to the comminion in the comminion in the comminion is second to the comminion in the comminio | n this application. If not include unication will be mailed in due o | d course. THIS |
| 1. This communication is responsive to | | | |
| 2. The allowed claim(s) is/are <u>1-18</u> . | | | |
| 3. Acknowledgment is made of a claim for foreign priority und a) All b) Some* c) None of the: | | or (f). | |
| 1. 🛛 Certified copies of the priority documents have | | | |
| 2. Certified copies of the priority documents have | • • | | |
| 3. Copies of the certified copies of the priority doc | uments have been received | d in this national stage applicati | on from the |
| International Bureau (PCT Rule 17.2(a)). | | | |
| * Certified copies not received: | | | |
| Applicant has THREE MONTHS FROM THE "MAILING DATE" of noted below. Failure to timely comply will result in ABANDONMI THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. | | e a reply complying with the requ | uirements |
| 4. A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which give | tted. Note the attached EXAs reason(s) why the oath or | AMINER'S AMENDMENT or NO declaration is deficient. | TICE OF |
| 5. CORRECTED DRAWINGS (as "replacement sheets") must | be submitted. | | |
| (a) including changes required by the Notice of Draftsperso | on's Patent Drawing Review | v (PTO-948) attached | |
| 1) hereto or 2) to Paper No./Mail Date | | | |
| (b) including changes required by the attached Examiner's Paper No./Mail Date | Amendment / Comment or | r in the Office action of | |
| Identifying indicia such as the application number (see 37 CFR 1.8 each sheet. Replacement sheet(s) should be labeled as such in the | 84(c)) should be written on the header according to 37 CF | ne drawings in the front (not the l R 1.121(d). | pack) of |
| 6. DEPOSIT OF and/or INFORMATION about the depos attached Examiner's comment regarding REQUIREMENT F | it of BIOLOGICAL MATE FOR THE DEPOSIT OF BIO | ERIAL must be submitted. N DLOGICAL MATERIAL. | ote the |
| | | | |
| Attachment(s) | | | |
| 1. Notice of References Cited (PTO-892) | | formal Patent Application (PTO | -152) |
| 2. Notice of Draftperson's Patent Drawing Review (PTO-948) | | ummary (PTO-413), /Mail Date | |
| 3. Information Disclosure Statements (PTO-1449 or PTO/SB/08 Paper No./Mail Date 02022004 | B), 7. ☐ Examiner's | Amendment/Comment | |
| Examiner's Comment Regarding Requirement for Deposit of Biological Material | 8. 🛛 Examiner's | Statement of Reasons for Allov | vance |
| | 9. | <u>-</u> : | |
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REASONS FOR ALLOWANCE

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1. The following is an examiner's statement of reasons for allowance:

The references of record do not teach or suggest a method comprising:

transferring the interconnect trench pattern to the sacrificial layer using the second photoresist as a mask; etching the first photoresist and the dielectric layer using the second photoresist as a mask, forming an interconnect trench, continuously etching the dielectric layer to form a via contact hole (claim 1).

forming a third photoresist having an interconnect trench pattern on the second photoresist; etching the second photoresist layer and transferring the interconnect trench pattern into the second photoresist using the third photoresist as mask; etching the first photoresist and the dielectric layer using the third photoresist as a mask; forming an interconnect trench, continuously etching the dielectric layer to form a via contact hole (claim 8).

2. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Kin-Chan Chen whose telephone number is (571) 272-1461. If attempts to reach the examiner by telephone are unsuccessful, the examiner's

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supervisor, Nadine Norton can be reached on (571) 272-1465. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Kin-Chan Chen Primary Examiner Art Unit 1765

November 23, 2005